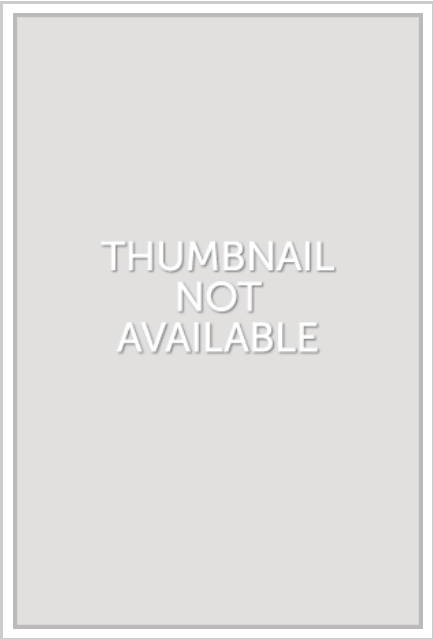


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Suite of Standards for Electromagnetic Material Characterization Using Mode Matching Theory

By Brian J. Witthoeft

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